TEXAS INSTRUMENTS

Data sheet acquired from Harris Semiconductor
SCHS221

November 1997

CD74HC40103, CD74HCT40103

High Speed CMOS Logic 8-Stage Synchronous Down Counters

Features

- **Synchronous or Asynchronous Preset**
- **Cascadable in Synchronous or Ripple Mode**
- **Fanout (Over Temperature Range)**
  - **Standard Outputs . . . . . 10 LSTTL Loads**
  - **Bus Driver Outputs . . . . . 15 LSTTL Loads**
- **Wide Operating Temperature Range . . . -55^{O}C to 125^{O}C**
- **Balanced Propagation Delay and Transition Times**
- **Significant Power Reduction Compared to LSTTL Logic ICs**
- **HC Types**
  - **2V to 6V Operation**
  - **High Noise Immunity: N_{IL} = 30%, N_{IH} = 30% of V_{CC} at V_{CC} = 5V**
- **HCT Types**
  - **4.5V to 5.5V Operation**
  - **Direct LSTTL Input Logic Compatibility, V_{IL}= 0.8V (Max), V_{IH} = 2V (Min)**
  - **CMOS Input Compatibility, $I_I \leq 1\mu A$ at V_{OL}, V_{OH}**

Ordering Information

PART NUMBER	TEMP. RANGE (^{O}C)	PACKAGE	PKG. NO.
CD74HC40103E	-55 to 125	16 Ld PDIP	E16.3
CD74HCT40103E	-55 to 125	16 Ld PDIP	E16.3
CD74HC40103M	-55 to 125	16 Ld SOIC	M16.15
CD74HCT40103M	-55 to 125	16 Ld SOIC	M16.15

NOTES:

1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
2. Wafer or die for this part number is available which meets all electrical specifications. Please contact your local sales office or Harris customer service for ordering information.

Description

The Harris CD74HC40103 and CD74HCT40103 are manufactured with high speed silicon gate technology and consist of an 8-stage synchronous down counter with a single output which is active when the internal count is zero. The 40103 contains a single 8-bit binary counter. Each has control inputs for enabling or disabling the clock, for clearing the counter to its maximum count, and for presetting the counter either synchronously or asynchronously. All control inputs and the $\overline{TC}$ output are active-low logic.

In normal operation, the counter is decremented by one count on each positive transition of the CLOCK (CP). Counting is inhibited when the $\overline{TE}$ input is high. The $\overline{TC}$ output goes low when the count reaches zero if the $\overline{TE}$ input is low, and remains low for one full clock period.

When the $\overline{PE}$ input is low, data at the P0-P7 inputs are clocked into the counter on the next positive clock transition regardless of the state of the $\overline{TE}$ input. When the $\overline{PL}$ input is low, data at the P0-P7 inputs are asynchronously forced into the counter regardless of the state of the $\overline{PE}$, $\overline{TE}$, or CLOCK inputs. Input P0-P7 represent a single 8-bit binary word for the 40103. When the MR input is low, the counter is asynchronously cleared to its maximum count of 255_{10}, regardless of the state of any other input. The precedence relationship between control inputs is indicated in the truth table.

If all control inputs except $\overline{TE}$ are high at the time of zero count, the counters will jump to the maximum count, giving a counting sequence of 100 or 256 clock pulses long.

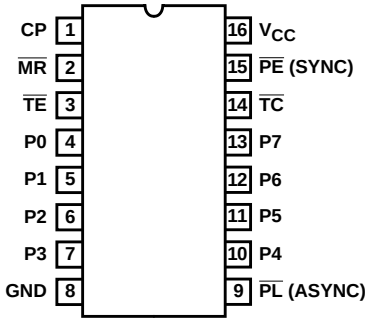
The 40103 may be cascaded using the $\overline{TE}$ input and the $\overline{TC}$ output, in either a synchronous or ripple mode. These circuits possess the the low power consumption usually associated with CMOS circuitry, yet have speeds comparable to low power Schottky TTL circuits and can drive up to 10 LSTTL loads.

CAUTION: These devices are sensitive to electrostatic discharge. Users should follow proper IC Handling Procedures.

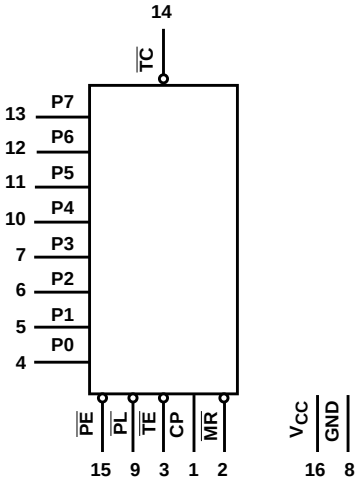
File Number **1596.1**

Pinout

CD74HC40103, CD74HCT40103
(PDIP, SOIC)
TOP VIEW



Functional Diagram



TRUTH TABLE

CONTROL INPUTS				PRESET MODE	ACTION
MR	PL	PE	TE		
1	1	1	1	Synchronous	Inhibit Counter
1	1	1	0		Count Down
1	1	0	X		Preset On Next Positive Clock Transition
1	0	X	X	Asynchronously	Preset Asychronously
0	X	X	X		Clear to Maximum Count

NOTE:
1 = High Level.
0 = Low Level.
X = Don't Care.
Clock connected to clock input.
Synchronous Operation: changes occur on negative-to-positive clock transitions.
Load Inputs: MSB = P7, LSB = P0.

Absolute Maximum Ratings

DC Supply Voltage, V_{CC} . . . . . -0.5V to 7V
DC Input Diode Current, I_{IK}
For V_I < -0.5V or V_I > V_{CC} + 0.5V . . . . . ±20mA
DC Output Diode Current, I_{OK}
For V_O < -0.5V or V_O > V_{CC} + 0.5V . . . . . ±20mA
DC Output Source or Sink Current per Output Pin, I_O
For V_O > -0.5V or V_O < V_{CC} + 0.5V . . . . . ±25mA
DC V_{CC} or Ground Current, I_{CC} . . . . . ±50mA

Operating Conditions

Temperature Range, T_A . . . . . -55^oC to 125^oC
Supply Voltage Range, V_{CC}
HC Types . . . . . 2V to 6V
HCT Types . . . . . 4.5V to 5.5V
DC Input or Output Voltage, V_I, V_O . . . . . 0V to V_{CC}
Input Rise and Fall Time
2V . . . . . 1000ns (Max)
4.5V. . . . . 500ns (Max)
6V . . . . . 400ns (Max)

Thermal Information

Thermal Resistance (Typical, Note 3) θ_{JA} ($^oC/W$)
PDIP Package 90
SOIC Package 160
Maximum Junction Temperature . . . . . 150^oC
Maximum Storage Temperature Range . . . . . -65^oC to 150^oC
Maximum Lead Temperature (Soldering 10s) . . . . . 300^oC
(SOIC - Lead Tips Only)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

3. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

DC Electrical Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
		V_I (V)	I_O (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES												
High Level Input Voltage	V_{IH}	-	-	2	1.5	-	-	1.5	-	1.5	-	V
				4.5	3.15	-	-	3.15	-	3.15	-	V
				6	4.2	-	-	4.2	-	4.2	-	V
Low Level Input Voltage	V_{IL}	-	-	2	-	-	0.5	-	0.5	-	0.5	V
				4.5	-	-	1.35	-	1.35	-	1.35	V
				6	-	-	1.8	-	1.8	-	1.8	V
High Level Output Voltage CMOS Loads	V_{OH}	V_{IH} or V_{IL}	-0.02	2	1.9	-	-	1.9	-	1.9	-	V
			-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
			-0.02	6	5.9	-	-	5.9	-	5.9	-	V
High Level Output Voltage TTL Loads			-	-	-	-	-	-	-	-	-	V
			-4	4.5	3.98	-	-	3.84	-	3.7	-	V
			-5.2	6	5.48	-	-	5.34	-	5.2	-	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	2	-	-	0.1	-	0.1	-	0.1	V
			0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
			0.02	6	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			-	-	-	-	-	-	-	-	-	V
			4	4.5	-	-	0.26	-	0.33	-	0.4	V
			5.2	6	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I_I	V_{CC} or GND	-	6	-	-	±0.1	-	±1	-	±1	µA
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	6	-	-	8	-	80	-	160	µA

DC Electrical Specifications (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
		V_I (V)	I_O (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HCT TYPES												
High Level Input Voltage	V_{IH}	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V
Low Level Input Voltage	V_{IL}	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage CMOS Loads	V_{OH}	V_{IH} or V_{IL}	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads			-4	4.5	3.98	-	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			4	4.5	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I_I	V_{CC} and GND	0	5.5	-	-	±0.1	-	±1	-	±1	µA
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	5.5	-	-	8	-	80	-	160	µA
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI_{CC}	V_{CC} -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	µA

NOTE: For dual-supply systems theoretical worst case (V_I = 2.4V, V_{CC} = 5.5V) specification is 1.8mA.

HCT Input Loading Table

INPUT	UNIT LOADS (NOTE)
P0-P7	0.20
$\overline{TE}$, $\overline{MR}$	0.40
CP	0.60
$\overline{PE}$	0.80
$\overline{PL}$	1.35

NOTE: Unit Load is ΔI_{CC} limit specified in DC Electrical Table, e.g., 360µA max at 25°C.

Prerequisite for Switching Specifications

PARAMETER	SYMBOL	V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES										
CP Pulse Width	t_W	2	165	-	-	205	-	250	-	ns
		4.5	33	-	-	41	-	50	-	ns
		6	28	-	-	35	-	43	-	ns
$\overline{PL}$ Pulse Width	t_W	2	125	-	-	155	-	190	-	ns
		4.5	25	-	-	31	-	38	-	ns
		6	21	-	-	26	-	32	-	ns

Prerequisite for Switching Specifications (Continued)

PARAMETER	SYMBOL	V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
$\overline{MR}$ Pulse Width	t_W	2	125	-	-	135	-	190	-	ns
		4.5	25	-	-	31	-	38	-	ns
		6	21	-	-	26	-	32	-	ns
CP Max. Frequency (Note 4)	$f_{CP(MAX)}$	2	3	-	-	2	-	2	-	MHz
		4.5	15	-	-	12	-	10	-	MHz
		6	18	-	-	14	-	12	-	MHz
P to CP Set-up Time	t_{SU}	2	100	-	-	125	-	150	-	ns
		4.5	20	-	-	25	-	30	-	ns
		6	17	-	-	21	-	26	-	ns
$\overline{PE}$ to CP Set-up Time	t_{SU}	2	75	-	-	95	-	110	-	ns
		4.5	15	-	-	19	-	22	-	ns
		6	13	-	-	16	-	19	-	ns
$\overline{TE}$ to CP Set-up Time	t_{SU}	2	150	-	-	190	-	225	-	ns
		4.5	30	-	-	38	-	45	-	ns
		6	26	-	-	33	-	38	-	ns
P to CP Hold Time	t_H	2	5	-	-	5	-	5	-	ns
		4.5	5	-	-	5	-	5	-	ns
		6	5	-	-	5	-	5	-	ns
$\overline{TE}$ to $\overline{CP}$ Hold Time	t_H	2	0	-	-	0	-	0	-	ns
		4.5	0	-	-	0	-	0	-	ns
		6	0	-	-	0	-	0	-	ns
$\overline{MR}$ to CP Removal Time	t_{REM}	2	50	-	-	65	-	75	-	ns
		4.5	10	-	-	13	-	15	-	ns
		6	9	-	-	11	-	13	-	ns
$\overline{PE}$ to $\overline{CP}$ Hold Time	t_H	2	2	-	-	2	-	2	-	ns
		4.5	2	-	-	2	-	2	-	ns
		6	2	-	-	2	-	2	-	ns
HCT TYPES										
CP Pulse Width	t_W	4.5	35	-	-	44	-	53	-	ns
$\overline{PL}$ Pulse Width	t_W	4.5	43	-	-	54	-	65	-	ns
$\overline{MR}$ Pulse Width	t_W	4.5	35	-	-	44	-	53	-	ns
CP Max. Frequency (Note 4)	$f_{CP(MAX)}$	4.5	14	-	-	11	-	9	-	MHz
P to CP Set-up Time	t_{SU}	4.5	24	-	-	30	-	36	-	ns
$\overline{PE}$ to CP Set-up Time	t_{SU}	4.5	20	-	-	25	-	30	-	ns
$\overline{TE}$ to CP Set-up Time	t_{SU}	4.5	40	-	-	50	-	60	-	ns
P to CP Hold Time	t_H	4.5	5	-	-	5	-	5	-	ns
$\overline{TE}$ to $\overline{CP}$ Hold Time	t_H	4.5	0	-	-	0	-	0	-	ns
$\overline{MR}$ to $\overline{CP}$ Removal Time	t_{REM}	4.5	10	-	-	13	-	15	-	ns
$\overline{PE}$ to $\overline{CP}$ Hold Time	tH	4.5	2	-	-	2	-	2	-	ns

Switching Specifications Input t_r, t_f = 6ns

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES											
Propagation Delay CP to any $\overline{TC}$ (Async Preset)	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	300	-	375	-	450	ns
		C_L = 50pF	4.5	-	-	60	-	75	-	90	ns
		C_L = 15pF	5	-	25	-	-		-		ns
		C_L = 50pF	6	-	-	51	-	64	-	77	ns
CP to $\overline{TC}$ (Sync Preset)	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	300	-	375	-	450	ns
		C_L = 50pF	4.5	-	-	60	-	75	-	90	ns
		C_L = 15pF	5	-	25	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	51	-	64	-	77	ns
$\overline{TE}$ to $\overline{TC}$	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	200	-	250	-	300	ns
		C_L = 50pF	4.5	-	-	40	-	50	-	60	ns
		C_L = 15pF	5	-	17	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	34	-	43	-	51	ns
$\overline{PL}$ to $\overline{TC}$	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	275	-	345	-	415	ns
		C_L = 50pF	4.5	-	-	55	-	69	-	83	ns
		C_L = 15pF	5	-	23	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	47	-	59	-	71	ns
$\overline{MR}$ to $\overline{TC}$	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	275	-	345	-	415	ns
		C_L = 50pF	4.5	-	-	55	-	69	-	83	ns
		C_L = 15pF	5	-	23	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	47	-	59	-	71	ns
Output Transition Time	t_{TLH}, t_{THL}	C_L = 50pF	2	-	-	75	-	95	-	110	ns
		C_L = 50pF	4.5	-	-	15	-	19	-	22	ns
		C_L = 50pF	6	-	-	13	-	16	-	19	ns
Input Capacitance	C_I	C_L = 50pF	-	-	-	10	-	10	-	10	pF
CP Maximum Frequency	f_{MAX}	C_L = 15pF	5	-	25	-	-	-	-	-	MHz
Power Dissipation Capacitance (Notes 5, 6)	C_{PD}	-	5	-	25	-	-	-	-	-	pF
HCT TYPES											
Propagation Delay CP to $\overline{TC}$ (Async Preset)	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	-	-	60	-	75	-	90	ns
		C_L = 15pF	5	-	25	-	-	-	-	-	ns
$\overline{CE}$ to $\overline{TC}$ (Sync Preset)	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	-	-	63	-	79	-	95	ns
		C_L = 15pF	5	-	26	-	-	-	-	-	ns
$\overline{TE}$ to $\overline{TC}$	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	-	-	50	-	63	-	75	ns
		C_L = 15pF	5	-	21	-	-	-	-	-	ns
$\overline{PL}$ to $\overline{TC}$	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	-	-	68	-	85	-	102	ns
		C_L = 15pF	5	-	28	-	-	-	-	-	ns

Switching Specifications Input t_r, t_f = 6ns **(Continued)**

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
$\overline{MR}$ to $\overline{TC}$	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	-	-	55	-	69	-	83	ns
		C_L = 15pF	5	-	23	-	-	-	-	-	ns
Output Transition Time	t_{THL}, t_{TLH}	C_L = 50pF	4.5	-	-	15	-	19	-	22	ns
Input Capacitance	C_{IN}	C_L = 50pF	-	-	-	10	-	10	-	10	pF
CP Maximum Frequency	f_{MAX}	C_L = 15pF	5	-	25	-	-	-	-	-	MHz
Power Dissipation Capacitance (Notes 5, 6)	C_{PD}	-	5	-	27	-	-	-	-	-	pF

NOTES:

4. Noncascaded operation only. With cascaded counters clock-to-terminal count propagation delays, count enables ($\overline{PE}$ or $\overline{TE}$)-to-clock SET UP TIMES, and count enables ($\overline{PE}$ or $\overline{TE}$)-to-clock HOLD TIMES determine maximum clock frequency. For example, with these HC devices:

$$C_P\ f_{MAX} = \frac{1}{\text{CP-to-}\overline{TC}\text{ prop delay} + \overline{TE}\text{-to-CP Setup Time} + \overline{TE}\text{-to-CP Hold Time}} = \frac{1}{60 + 30 + 0} \approx 11\text{MHz}$$

5. C_{PD} is used to determine the dynamic power consumption, per package.
6. $P_D = V_{CC}^2\ f_i + C_L\ V_{CC}^2\ f_o$ where f_i = Input Frequency, C_L = Output Load Capacitance, V_{CC} = Supply Voltage, f_o = Output Frequency.

Timing Diagrams

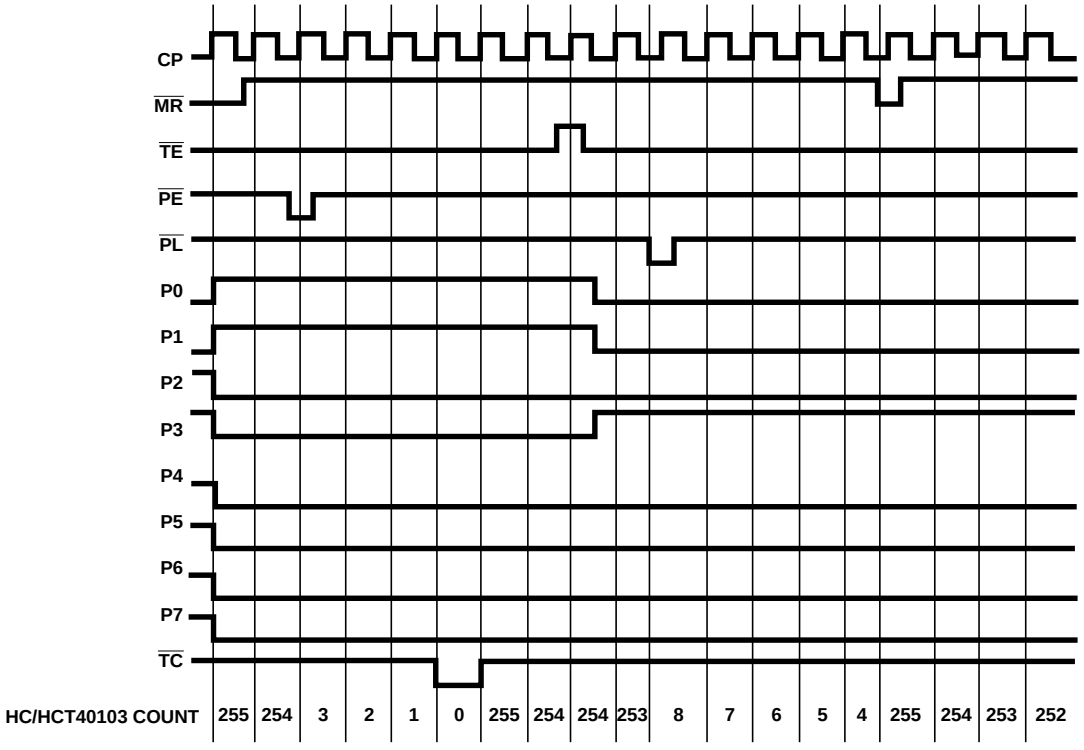


FIGURE 2.

Test Circuits and Waveforms

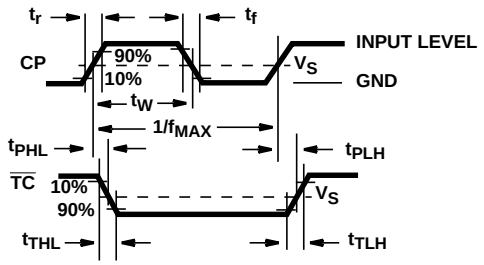


FIGURE 3.

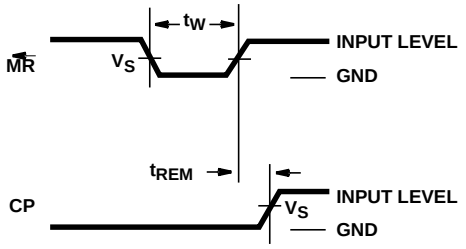


FIGURE 4.

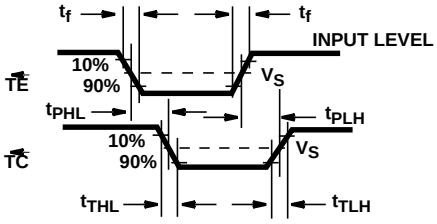


FIGURE 5.

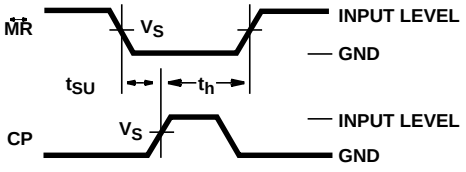


FIGURE 6.

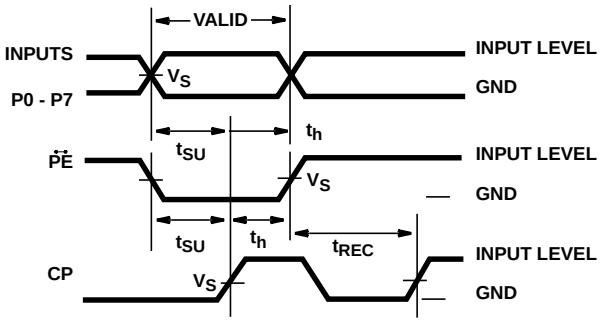


FIGURE 7.

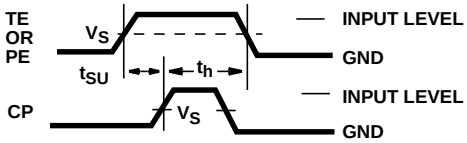
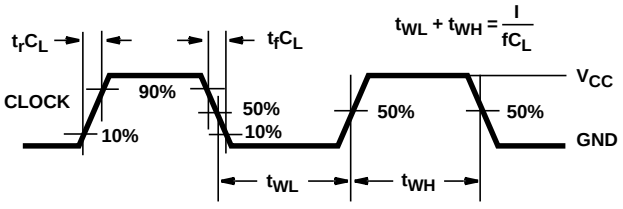
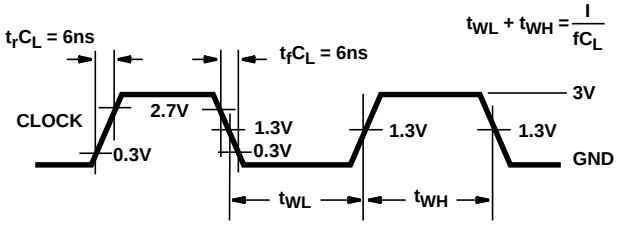


FIGURE 8.



NOTE: Outputs should be switching from 10% V_{CC} to 90% V_{CC} in accordance with device truth table. For f_{MAX}, input duty cycle = 50%.

FIGURE 9. HC CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH



NOTE: Outputs should be switching from 10% V_{CC} to 90% V_{CC} in accordance with device truth table. For f_{MAX}, input duty cycle = 50%.

FIGURE 10. HCT CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH

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